

| FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) | | | | ATTY DOCKET NO. 03560.003316. | | APPLICATION NO. 10/606,956 | |
|---|---|----------|----------------|---|----------|---------------------------------------|--|
| APPLICANT HIDETOSHI TSUZUKI ET AL. | | | | FILING DATE June 27, 2003 | | GROUP Unassigned | |
| U.S. PATENT DOCUMENTS | | | | | | | |
| *EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE | |
| LV | 5,804,466 | 09/08/98 | Arao et al. | 438 | 95 | | |
| | 6,068,755 | 05/30/00 | Matsuda et al. | 205 | 333 | | |
| | 6,077,411 | 06/20/00 | Nakamura | 205 | 138 | | |
| | 6,133,061 | 10/17/00 | Sonoda | 438 | 69 | | |
| | 6,346,184 B1 | 02/12/02 | Sano et al. | 205 | 199 | | |
| | 2002/0063065 A1 | 05/30/02 | Sonoda et al. | 205 | 333 | | |
| LV | 6,576,112 B2 | 06/10/03 | Sonoda et al. | 205 | 155 | 09/17/01 | |
| FOREIGN PATENT DOCUMENTS | | | | | | | |
| | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES/NO/ OR ABSTRACT | |
| LV | JP 10-60686 | 03/03/98 | Japan | | | Abstract | |
| | JP 10-140373 | 05/26/98 | Japan | | | Abstract & USP 5804466 | |
| | JP 10-195693 | 07/28/98 | Japan | | | Abstract & USP 5804466 | |
| | JP 10-259496 | 09/29/98 | Japan | | | Abstract & USP 6077411 | |
| | JP 11-286799 | 10/19/99 | Japan | | | Abstract & USP 6133061 | |
| | JP 2002-155396 | 05/31/02 | Japan | | | Abstract | |
| LV | JP 2002-167695 | 06/11/02 | Japan | | | Abstract & USP 6576112 | |
| OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | |
| LV | Sannomiya, et al.; "a-SiC/a-Si/a-SiGe Multi-Bandgap Stacked Solar Cells With Bandgap Profiling"; Int'l PVSEC-5, 387-390 (1990). | | | | | | |
| | Inoue, et al.; "A light confinement effect in an a-SiGe solar cell on a 29 p-MF-22 stainless steel substrate"; Extended Abstracts Japan Soc. Applied Physics, 29-MF-2, p. 747 (1990). | | | | | | |
| EXAMINER <i>Shan Van</i> | | | | DATE CONSIDERED <i>6/8/25</i> | | | |

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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